

<b>Notice of References Cited</b>	Application/Control No. 10/509,745		Applicant(s)/Patent Under Reexamination KAWAGUCHI ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,476,700 A	12-1995	Asai et al.	428/66.6
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**NON-PATENT DOCUMENTS**

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	U	
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